

**UNIVERSITY OF MUMBAI**



**Bachelor of Engineering**

**BACHELOR OF ELECTRONICS AND  
TELECOMMUNICATION ENGINEERING**

**Second Year (Semester III And IV), Revised Course  
(Rev2012) From Academic Year 2013-14**

(As per Credit Based Semester and Grading System with  
effect from the academic year 2012–2013)

Sub Code	Subject Name	Teaching Scheme (Hrs.)			Credits Assigned			
		Theory	Practical	Tutorial	Theory	Practical	Tutorial	Total
ETS301	Applied Mathematics III	04	--	01	04	--	01	05
ETC302	Analog Electronics I	04	--	--	04	--	--	04
ETC303	Digital Electronics	04	--	--	04	--	--	04
ETC304	Circuits and Transmission Lines	04	--	--	04	--	--	04
ETC305	Electronic Instruments and Measurements	04	--	--	04	--	--	04
ETC306	Object Oriented Programming Methodology	02	--	--	--	--	--	--
ETL301	Analog Electronics I Laboratory	--	02	--	--	01	--	01
ETL302	Digital Electronics Laboratory	--	02	--	--	01	--	01
ETL303	Circuits and Measurement Laboratory	--	02	--	--	01	--	01
ETL304	Object Oriented Programming Methodology, Laboratory	02	02	--	--	01	--	01
Total		24	08	01	20	04	01	25

Subject Code	Subject Name	Examination Scheme							Total
		Theory Marks			End Sem. Exam	Term Work	Practical and Oral	Oral	
		Internal assessment		Avg. of Test 1 & Test 2					
Test 1	Test 2								
ETS301	Applied Mathematics III	20	20	20	80	25	--	--	125
ETC302	Analog Electronics I	20	20	20	80	--	--	--	100
ETC303	Digital Electronics	20	20	20	80	--	--	--	100
ETC304	Circuits and Transmission Lines	20	20	20	80	--	--	--	100
ETC305	Electronic Instruments and Measurements	20	20	20	80	--	--	--	100
ETC306	Object Oriented Programming Methodology	--	--	--	--	--	--	--	--
ETL301	Analog Electronics I Laboratory	--	--	--	--	25	50	--	75
ETL302	Digital Electronics Laboratory	--	--	--	--	25	50	--	75
ETL303	Circuits and Measurement Laboratory	--	--	--	--	25	--	--	25
ETL304	Object Oriented Programming Methodology, Laboratory	--	--	--	--	25	50	--	75
		--	--	100	400	125	150	--	775

Subject Code	Subject Name	Teaching Scheme			Credits Assigned			
		Theory	Practical	Tutorial	Theory	Practical	Tutorial	Total
ETC 301	Applied Mathematics III	04	--	01	04	-	01	05

Subject Code	Subject Name	Examination Scheme								
		Theory Marks					Term Work	Practical	Oral	Total
		Internal assessment			End Sem. Exam					
		Test 1	Test 2	Avg. Of Test 1 and Test 2						
ETC 301	Applied Mathematics III	20	20	20	80	25	--	--	125	

**Course Pre-requisite:**

FE C 101 : Applied Mathematics I  
 FE C 201 : Applied Mathematics II

- To provide students with a sound foundation in Mathematics and prepare them for graduate studies in Electronics and Telecommunication Engg.
- To provide students with mathematics fundamental necessary to formulate, solve and analyze engg. problems.
- To provide opportunity for students to work as part of teams on multi disciplinary projects.

**Expected Outcomes:**

- Students will demonstrate basic knowledge of Laplace Transform. Fourier Series, Bessel Functions, Vector Algebra and Complex Variable.
- Students will demonstrate an ability to identify formulate and solve electronics and telecommunication Engg. problem using Applied Mathematics.
- Students will show the understanding of impact of Engg. mathematics on Telecom Engg.
- Students who can participate and succeed in competitive exams like GATE, GRE.

Module No.	Unit No.	Topics	Hrs.
1.0		<b>Laplace Transform</b>	12
	1.1	<b>Laplace Transform (LT) of Standard Functions:</b> Definition. Unilateral and bilateral Laplace Transform, LT of $\sin(at)$ , $\cos(at)$ , $e^{at}$ , $t^n$ , $\sinh(at)$ , $\cosh(at)$ , $\operatorname{erf}(t)$ , Heavi-side unit step, direct- delta Function, LT of periodic Function	
	1.2	<b>Properties of Laplace Transform:</b> linearity, first shifting theorem, second shifting theorem, multiplication by $t^n$ , division by $t$ , Laplace Transform of derivatives and integrals, change of scale, convolution theorem, initial and final value theorem, Parseval's identity	
	1.3	<b>Inverse Laplace Transform:</b> Partial fraction method, long division method, residue method	
	1.4	<b>Applications of Laplace Transform :</b> Solution of ordinary Differential Equations	
2.0		<b>Fourier Series</b>	10
	2.1	<b>Introduction:</b> Definition, Dirichlet's conditions, Euler's formulae	
	2.2	<b>Fourier Series of Functions:</b> exponential, trigonometric Functions, even and odd Functions, half range sine and cosine series	
	2.3	Complex form of Fourier series, orthogonal and orthonormal set of Functions Fourier integral representation	
3.0		<b>Bessel Functions</b>	08
	3.1	<b>Solution of Bessel Differential Equation:</b> series method, recurrence relation, properties of Bessel Function of order $+1/2$ and $-1/2$	
	3.2	Generating Function, orthogonality property	
	3.3	Bessel Fourier series of a Functions	
4.0		<b>Vector Algebra</b>	12
	4.1	<b>Scalar and Vector Product:</b> Sclar and Vector Product of three and four vectors and their properties	
	4.2	<b>Vector Differentiation :</b> Gradient of scalar point Function, divergence and curl of vector point Function	
	4.3	<b>Properties:</b> Solenoidal and Irrotational vector fields, conservative vector field	
	4.4	<b>Vector Integral:</b> Line integral, Green's theorem in a plane, Gauss Divergence theorem, Stokes' theorem	
5.0		<b>Complex Variable</b>	10
	5.1	<b>Analytic Function:</b> Necessary and sufficient conditions, Cauchy Reiman. Equations in polar form	
	5.2	Harmonic Function, orthogonal trajectories	
	5.3	<b>Mapping:</b> Conformal mapping, bilinear Transformations, cross ratio, fixed points, bilinear Transformation of straight lines and circles.	
		<b>Total</b>	<b>52</b>

**Text books:**

- 1) P. N. Wartilar and J. N. Wartikar, "A Text Book of Applied Mathematic", Vol. I & II, Vidyarthi Griha Prakashan, Pune
- 2) A Datta, "Mathematical Methods in Science and Engineerin", 2012
- 3) Dr. B.S. Grewal, "Higher Engineering Mathematics", Khanna Publication

**Reference Books:**

- 1) B. S. Tyagi, "Functions of a Complex Variable," Kedarnath Ram Nath Publication
- 2) B V Ramana, "Higher Engineering Mathematics", Tata McGraw-Hill Publication
- 3) Wylie and Barret, "Advanced Engineering Mathematics", McGraw-Hill 6th Edition
- 4) Erwin Kreysizg, "Advanced Engineering Mathematics", John Wiley & Sons, Inc
- 5) Murry R. Spieget, "Vector Analysis", Schaun's Out Line Series, McGraw Hill Publication

**Internal Assessment (IA):**

Two tests must be conducted which should cover at least 80% of syllabus. The average marks of both the tests will be considered for final Internal Assessment.

**End Semester Examination:**

1. Question paper will comprise of 6 questions, each carrying 20 marks.
2. The students need to solve total 4 questions.
- 3: Question No.1 will be compulsory and based on entire syllabus.
- 4: Remaining question (Q.2 to Q.6) will be selected from all the modules.
- 5: Weightage of marks will be as per Blueprint.

**Term Work:**

At least 08 assignments covering entire syllabus must be given during the **Class Wise Tutorial**. The assignments should be students' centric and an attempt should be made to make assignments more meaningful, interesting and innovative.

Term work assessment must be based on the overall performance of the student with every assignment graded from time to time. The grades will be converted to marks as per **Credit and Grading System** manual and should be added and averaged. Based on above scheme grading and term work assessment should be done.

Subject Code	Subject Name	Teaching Scheme			Credits Assigned			
		Theory	Practical	Tutorial	Theory	TW/Practical	Tutorial	Total
ETC 302	Analog Electronics I	4	--	--	4	01	--	05

Subject Code	Subject Name	Examination Scheme								
		Theory Marks					Term Work	Practical and Oral	Oral	Total
		Internal assessment			End Sem. Exam					
		Test 1	Test 2	Avg. Of Test 1 and Test 2						
ETC 302	Analog Electronics I	20	20	20	80	25	50	-	175	

**Course Pre-requisite:**

- FEC102 Applied Physics
- FEC105 Basic Electricity and Electronics

**Course Objective:**

- To understand physical operation of semiconductor devices
- To understand DC and AC models of semiconductor devices
- To apply concepts of DC and AC modeling of semiconductor devices for the design and analysis
- To verify the theoretical concepts through laboratory and simulation experiments.

**Expected Outcomes:**

After completion of this course students will be:

- Able to understand the current voltage characteristics of semiconductor devices.
- Able to understand and relate dc and ac models of semiconductor devices with their physical Operation.
- Able to perform dc and ac analysis of the basic electronic Circuits
- Able to design analog system and components.

Module No.	Unit No.	Topics	Hrs.
1.0	1.0	<b>Diodes and its Applications</b>	08
	1.1	<b>PN Junction Diode:</b> Diode current equation, effect of temperature on diode characteristics, breakdown mechanism, diode as a switch, small signal model	
	1.2	<b>Clippers and Clampers:</b> voltage transfer characteristics, series and shunt clippers, single diode series and shunt clamper Circuits	
	1.3	<b>Other PN junction devices:</b> Construction and operation of Varactor diode, photodiode, Schottkey diode ( no numericals for this unit)	
2.0	2.0	<b>Field Effect Transistors</b>	10
	2.1	<b>Junction Field Effect Transistor (JFET):</b> Construction, working, regions of operation, transfer ( $V_{GS}$ Vs $I_D$ ) and output ( $V_{DS}$ Vs $I_D$ ) characteristics, Schockely equation	
	2.2	<b>Metal-Oxide Effect Transistor (MOSFET):</b> <b>E-MOSFET:</b> MOS capacitor, energy band diagram of MOS capacitor in accumulation, depletion and inversion region, concept of threshold voltage, operation of MOSFET, derivation of threshold voltage and drain current, body effect, channel length modulation <b>D-MOSFET:</b> Construction and working	
3.0	3.0	<b>DC Analysis of Transistor Circuits</b>	10
	3.1	<b>Bipolar Junction Transistor:</b> Review of BJT Characteristics, DC load line and regions of operation, transistor as a switch, DC analysis of common BJT Circuits, analysis and design of fixed bias, collector to base bias and voltage divider bias, stability factor analysis	
	3.2	<b>Junction Field Effect Transistor:</b> Analysis and design of self bias and voltage divider bias	
	3.3	<b>MOSFET:</b> DC load line and region of operation, common MOSFETs configurations, analysis and design of biasing Circuits	
4.0	4.0	<b>Small Signal Analysis of BJT Amplifiers</b>	08
	4.1	<b>BJT CE Amplifier:</b> understanding of amplification concept with reference to input/output characteristics, AC load line analysis, definition of Amplifier parameters $Z_i, Z_o, A_v$ and $A_i$ , graphical analysis to evaluate parameters	
	4.2	<b>Small Signal mid Frequency Models:</b> hybrid-pi model, early effect, h-parameter model	
	4.3	<b>Small Signal Analysis:</b> small signal analysis (mid-frequency) ( $Z_i, Z_o, A_v$ and $A_i$ ) of CE, CB, and CC configurations using hybrid-pi model, comparison between CE, CB, and CC configurations with reference to parameters	
5.0	5.0	<b>Small Signal Analysis of FET Amplifiers</b>	08
	5.1	<b>JFET CS Amplifier:</b> Small signal equivalent Circuit and analysis (mid-frequency) ( $Z_i, Z_o,$ and $A_v$ )	
	5.2	<b>E-MOSFET Amplifier:</b> Graphical analysis to evaluate parameters, AC load line, small signal model, small signal (mid-frequency) analysis of CS, CD, and CG Amplifiers	
6.0	6.0	<b>Oscillators ( no numericals)</b>	08
	6.1	<b>Concepts of Oscillator:</b> Concept of negative and positive feedback and condition for Oscillation	
	6.2	<b>RC oscillators:</b> Phase Shift and Wein Bridge	
	6.3	<b>LC Oscillators:</b> Hartley, Colpitts, and Clapps	
	6.4	<b>Tuned Oscillator:</b> Twin T oscillator and Crystal Oscillator	
		<b>Total</b>	<b>52</b>

**Text Books:**

1. Donald A. Neamen, *“Electronic Circuit Analysis and Design”*, TATA McGraw Hill, 2<sup>nd</sup> Edition
2. Adel S. Sedra, Kenneth C. Smith, and Arun N Chandorkar, *“Microelectronic Circuits Theory and Applications”*, International Version, OXFORD International Students, Fifth Edition

**Recommended Books:**

- 1) Sung-Mo (Steve) Kang, and Yusuf Leblebici, *“CMOS Digital Integrated Circuits Analysis and Design”*, TATA McGraw Hill
- 2) Salivan, *“Electronic Devices and Circuits”*, Publication
- 3) Jacob Millima, *“Electronic Devices and Circuits”*, Publication
- 4) Rashid, *“Electronic Devices and Circuits”*, Publication
- 5) Anil K. Maini and Varsha Agrawal, *“Electronic Devices and Circuits”*, Wiley Publications

**Internal Assessment (IA):**

Two tests must be conducted which should cover at least 80% of syllabus. The average marks of both the tests will be considered for final Internal Assessment.

**End Semester Examination:**

1. Question paper will comprise of 6 questions, each carrying 20 marks.
2. The students need to solve total 4 questions.
- 3: Question No.1 will be compulsory and based on entire syllabus.
- 4: Remaining question (Q.2 to Q.6) will be selected from all the modules.
- 5: Weightage of marks will be as per Blueprint.



Subject Code	Subject Name	Teaching Scheme			Credits Assigned			
		Theory	Practical	Tutorial	Theory	TW/ Practical	Tutorial	Total
ETC 302	Analog Electronics I Laboratory	--	02	--	--	01	--	01

Subject Code	Subject Name	Examination Scheme								
		Theory Marks					Term Work	Practical and Oral	Oral	Total
		Internal assessment			End Sem. Exam					
		Test 1	Test 2	Avg. Of Test 1 and Test 2						
ETC 302	Analog Electronics I Laboratory	--	--	--	--	25	50	-	75	

**Term Work:**

At least **10** experiments covering entire syllabus should be set to have well predefined inference and conclusion. Computation/simulation based experiments are also encouraged. The experiments should be students' centric and attempt should be made to make experiments more meaningful, interesting and innovative.

Term work assessment must be based on the overall performance of the student with every experiment graded from time to time. The grades will be converted to marks as per **Credit and Grading** System manual and should be added and averaged. Based on the above scheme grading and term work assessment should be done.

**The Practical / Oral examination will be based on entire syllabus.**

Subject Code	Subject Name	Teaching Scheme			Credits Assigned			
		Theory	Practical	Tutorial	Theory	TW/ Practical	Tutorial	Total
ETC 303	Digital Electronics	04	--	--	04	01	--	05

Subject Code	Subject Name	Examination Scheme							
		Theory Marks				Term Work	Practical and oral	Oral	Total
		Internal assessment			End Sem. Exam				
		Test 1	Test 2	Avg. of Test 1 and Test 2					
ETC303	Digital Electronics	20	20	20	80	25	50	-	175

**Course Pre-requisite:**

**Course Objective:**

- To introduce the fundamental concepts and methods for design of various digital Circuits.
- To build the skill of digital system design and testing used in various fields of computing, communication, automatic control of mechanisms and instrumentation.

**Expected Outcomes:**

After completion of course, students will be

- Able to distinguish between Digital & Analog signals & data.
- Able to analyze, Transform & minimize combination logic Circuits.
- Understanding of basic arithmetic Circuits.
- Able to design and analyze sequential Circuits.
- Counter to solve a real-world problem.
- Able to design digital system and components.

Module No.	Unit No.	Topics	Hrs.
1.0		<b>Number Systems and Codes</b>	04
	1.1	<b>Arithmetic codes:</b> Review of number system, BCD code, Octal code, Hexadecimal code, EX-3 code, Gray code, ASCII Code	
2.0		<b>Logic Gates and Combinational Logic Circuits</b>	16
	2.1	<b>DTL,TTL,ECL, and CMOS gates:</b> transfer characteristics, noise margin, fan in fan out Introduction to logic families, DTL, TTL, ECL & CMOS with taking into account their transfer characteristics, noise margin, fan in fan out.	
	2.2	<b>Universal gates and combinational Circuits:</b> Realization of basic gates using NAND and NOR gates, Boolean Algebra, De Morgan's Theorem, SOP and POS representation, K-map up to five variables and Quine-McClusky method, Variable Entered Mapping	
	2.3	<b>Arithmetic Circuits:</b> Adders, subtractor, Carry look ahead adder, BCD adder, magnitude comparator, binary multiplier, series and parallel address.	
	2.4	<b>Multiplexer and De-multiplexer:</b> Boolean Functions implementation using Multiplexer and De-multiplexer, Encoder and Decoder, Parity generator and checkers	
3.0		<b>Sequential Logic Circuits</b>	16
	3.1	<b>Flip flops and Registers:</b> RS, JK, T D and Master slave flip flops, , conversion of flip flops, Universal shift registers	
	3.2	<b>Counter design:</b> Asynchronous and synchronous counter, up/down counters, MOD-N counters, pre-settable counters, skipping state counters.	
	3.3	<b>Shift Registers Design:</b> SISO, SIPO, PISO, PIPO, shift left and shift right registers	
	3.4	<b>Applications of Sequential Circuits:</b> Frequency division, Ring counter, Johnson counter, Moore and Mealy machine, state transition diagram, synthesis table	
	3.6	<b>State reduction techniques:</b> Row elimination and implication table methods	
4.0		<b>Different types of Memory</b>	06
	4.1	<b>Classification and Characteristics of Memory:</b> SRAM, DRAM, ROM, PROM, EPROM and FLASH memories	
5.0		<b>Introduction to Programmable Logic Devices</b>	10
	5.1	<b>CPLD and FPGA:</b> Architecture of CPLD and FPGA, Xilinx XC 9500 CPLD Series and Xilinx XC 4000 FPGA Series <b>VHDL:</b> Data types, Structural Modeling using VHDL, attributes, data flow, behavioral, VHDL implementation of basic combinational and sequential Circuits	
	5.2	<b>Programmable Logic Devices:</b> PLA and PAL	
		<b>Total</b>	<b>52</b>

**Text Books:**

1. Malvino
2. J. Bhaskar, "VHDL Primer", Prentice Hall, 3<sup>rd</sup> Edition

**Reference Books:**

1. Floyed and Jain, "Digital fundamentals", Pearson Education, 8<sup>th</sup> Edition
2. S. Brown and Z. Vranesic, "Fundamentals of Digital Logic Design with VHDL", Tata McGrawHill, 2<sup>nd</sup> Edition
3. John F. Warkerly, "Digital Design Principles and Practices", Person Education, 4<sup>th</sup> Edition
4. Lee S.C, "Digital Circuit and Logic Design", Prentice Hall of India," 2007
5. Malvino A.P. and Leach D.P., "Digital Principles and Applications", TMH, 6<sup>th</sup> Edition
6. R. P. Jain, "Modern Digital Electronics", Tata McGraw-Hill, 4<sup>th</sup> Edition
7. Brian Holdsworth and Clive Woods, "Digital Logic Design", Oxford Newnes, 4<sup>th</sup> Edition

**Internal Assessment (IA):**

Two tests must be conducted which should cover at least 80% of syllabus. The average marks of both the tests will be considered for final Internal Assessment.

**End Semester Examination:**

1. Question paper will comprise of 6 questions, each carrying 20 marks.
2. The students need to solve total 4 questions.
3. Question No.1 will be compulsory and based on entire syllabus.
4. Remaining question (Q.2 to Q.6) will be selected from all the modules.
5. Weightage of marks will be as per Blueprint.

Subject Code	Subject Name	Teaching Scheme			Credits Assigned			
		Theory	Practical	Tutorial	Theory	TW/ Practical	Tutorial	Total
ETC 303	Digital Electronics Laboratory	--	02	--	--	01	--	01

Subject Code	Subject Name	Examination Scheme							
		Theory Marks				Term Work	Practical and oral	Oral	Total
		Internal assessment			End Sem. Exam				
		Test 1	Test 2	Avg. of Test 1 and Test 2					
ETC303	Digital Electronics Laboratory	--	--	--	--	25	50	-	75

**Term Work:**

At least **10** experiments covering entire syllabus should be set to have well predefined inference and conclusion. Computation/simulation based experiments are also encouraged. The experiments should be students' centric and attempt should be made to make experiments more meaningful, interesting and innovative.

Term work assessment must be based on the overall performance of the student with every experiment graded from time to time. The grades will be converted to marks as per **Credit and Grading** System manual and should be added and averaged. Based on the above scheme grading and term work assessment should be done.

**The Practical / Oral examination will be based on entire syllabus.**

Subject Code	Subject Name	Teaching Scheme			Credits Assigned			
		Theory	Practical	Tutorial	Theory	TW/ Practical	Tutorial	Total
ETC 304	Circuits and Transmission Lines	04	--	--	04	--	--	04

Subject Code	Subject Name	Examination Scheme							
		Theory Marks				Term Work	Practical	Oral	Total
		Internal assessment			End Sem. Exam				
		Test 1	Test 2	Avg. of 2 Tests					
ETC 304	Circuits and Transmission Lines	20	20	20	80	--	--	--	100

**Course Pre-requisite:**

FEC 105: Basic Electrical and Electronics Engg.  
Laplace Transform, Differential Equations

**Course Objective:**

- To analyze and synthesize Circuits and to become familiar with the propagation of signals through transmission lines.
- To analyze the Circuits in time and frequency domain
- To study network Functions, inter relationship among various Circuits' parameters, solve more complex network using these parameters.

**Program Education Objectives:**

- Through test, laboratory exercises and home assignment, students will be able to apply their knowledge in solving complex Circuits.
- Students will be able to evaluate the time and frequency response which is useful in understanding behavior of Electronics Circuits and Control System.
- Student will be able to understand how the information in terms of voltage and current is transmitted through the transmission lines and importance of matching.

Module No.	Unit No.	Topics	Hrs.
1.0		<b>Electrical Circuit Analysis of Mutually Exclusive and Coupled Circuits</b>	12
	1.1	<b>Analysis of DC Circuits:</b> Analysis of Circuits with and without controlled sources using generalized loop and node matrix methods <b>Circuit Theorems:</b> Source Transformation, Superposition, Thevenin, Norton, Millman	
	1.2	<b>Self and Mutual Inductances:</b> Self and mutual inductances, coefficient of coupling, Dot convention, equivalent Circuit, solution using loop analysis	
	1.3	<b>Tuned coupled Circuits:</b> Analysis of tuned coupled Circuits	
2.0		<b>Time and Frequency Domain Analysis</b>	10
	2.1	<b>Time domain analysis of R-L and R-C Circuits:</b> Forced and natural response, time constant, initial and final values <b>Solution using first order equation for standard input signals:</b> transient and steady state time response, solution using universal formula	
	2.2	<b>Time domain analysis of R-L-C Circuits:</b> Forced and natural response, effect of damping <b>Solution using second order equation for standard input signals:</b> transient and steady state time response	
	2.3	<b>Frequency domain analysis of RLC Circuits:</b> S - domain representation, applications of Laplace Transform in solving electrical networks, driving point and transfer Function, Poles and Zeros, calculation of residues by analytical and graphical method, analysis of ladder and lattice network <b>Response to standard signals:</b> transient and steady state time response of R-L-C Circuits	
3.0		<b>Synthesis of RLC Circuits</b>	10
	3.1	<b>Positive Real Functions:</b> Concept of positive real Function, testing for Hurwitz polynomials, testing for necessary and sufficient conditions for Positive real Functions	
	3.2	<b>Synthesis of RC, RL, LC Circuits:</b> properties and synthesis of RC, RL, LC driving point Functions	
4.0		<b>Two Port Circuits</b>	08
	4.1	<b>Parameters:</b> Open Circuits, short Circuit, Transmission and Hybrid parameters, relationship among parameters, Reciprocity and symmetry conditions.	
	4.2	Interconnections of Two-Port Circuits, T & $\Pi$ representation.	
	4.3	Terminated Two-port Circuits.	
5.0		<b>Radio Frequency Transmission Lines</b>	10
	5.1	<b>Transmission Line Representation:</b> T and $\Pi$ representations, terminated transmission line, infinite line	
	5.2	<b>Parameters of Radio Frequency Lines:</b> Propagation constant, attenuation constant, phase constant, group velocity, input impedance, characteristic impedance, reflection coefficient, standing wave ratio, VSWR, ISWR, S-parameters	
	5.3	<b>Smith Chart:</b> impedance locus diagram, impedance matching	
		<b>Total</b>	<b>52</b>

**Text Books**

1. Franklin F Kuo, "*Network Analysis and Synthesis*", Wiley Toppan, 2nd.ed. 1966
2. W L Everitt and G E Anner, "*Communication Engineering*", Mc-GrawHill, New York, 3<sup>rd</sup> Edition, 1956

**Reference Books**

1. M E Van Valkenburg, "*Network Analysis*", Prentice-Hall of India Pvt Ltd, New Delhi, 26<sup>th</sup> Indian Reprint, 2000
2. K V V Murty and M S Kamth, "*Basic Circuit Analysis*", Jaico Publishing house, London
3. A Chakrabarti, "*Circuit Theory*", Dhanpat Rai & Co., Delhi, 6h Edition

**Internal Assessment (IA):**

Two tests must be conducted which should cover at least 80% of syllabus. The average marks of both the test will be considered for final Internal Assessment.

**End Semester Examination:**

1. Question paper will comprise of 6 questions, each carrying 20 marks.
2. The students need to solve total 4 questions.
- 3: Question No.1 will be compulsory and based on entire syllabus.
- 4: Remaining question (Q.2 to Q.6) will be selected from all the modules.
- 5: Weightage of marks will be as per Blueprint.

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Subject Code	Subject Name	Teaching Scheme			Credits Assigned			
		Theory	Practical	Tutorial	Theory	TW/ Practical	Tutorial	Total
ETC 405	Electronic Instruments and Measurements	04	--	--	04	--	--	04

Subject Code	Subject Name	Examination Scheme								
		Theory Marks				End Sem. Exam	Term Work	Practical and oral	Oral	Total
		Internal assessment			Avg. Of Test 1 and Test 2					
		Test 1	Test 2							
ETC 405	Electronic Instruments and Measurements	20	20	20	80	--	--	--	100	

**Pre-requisites:**

- Students are expected to have knowledge of the basic electronics Circuits including analog and digital electronics

**Course Objective:**

- To understand basic Functions and principle of working of sensors and components used in Electronic Measurement
- To understand Principles of Advanced Electronic Instruments and application in measurement of electronics parameters

**Course Outcome:**

- Students will learn measurement of physical parameters using various transducers and working of sensors.
- They will become familiar with basics of instruments and details of operation of measuring instruments and their applications.

Module No.	Unit No.	Topics	Hrs.
1.0		<b>Principals of Measurement</b>	06
	1.1	<b>Introduction to Basic Instruments:</b> Components of Generalized measurement system, applications of instrument systems, static and dynamic characteristics of instruments, concepts of accuracy, precision, linearity, sensitivity, resolution, hysteresis, calibration	
	1.2	<b>Errors in Measurement:</b> Errors in measurement, classification of errors, remedies to eliminate errors	
2.0		<b>Sensors and Transducers</b>	12
	2.1	<b>Basics of Sensors and Transducers:</b> Active and Passive transducers, characteristics and selection criteria of transducers, working principle of Eddy-Current Sensors, Pizeoelectric Transducers, Photoelectric and Photo Voltaic Sensors, Capacitance Sensors	
	2.2	<b>Displacement and Pressure:</b> Potentiometers, pressure gauges, Linear Variable Differential Transformers for measurement of pressure and displacement, Strain Gauges	
	2.3	<b>Temperature Transducers:</b> Resistance Temperature Detectors, Thermistors, and Thermocouples, their ranges and applications	
3.0		<b>Testing and Measuring Instruments</b>	10
	3.1	<b>Analog Multi-meter:</b> Multi-range measurement of voltage, current and resistance, specifications	
	3.2	<b>Measurement Resistance:</b> Kellvin's Double Bridge, Wheatstone bridge, and Megaohm Bridge <b>Measurement of Inductance:</b> Maxwell Bridge and Hey Bridge; <b>Measurement of Capacitance:</b> Schering Bridge <b>Q-Meter:</b> Operating principle and applications	
	3.3	<b>Energy and Power Meters:</b> Working of energy and power Meter	
4.0		<b>Data Acquisition and Digital Instruments</b>	10
	4.1	<b>Data Acquisition and Converters:</b> Single channel, Multichannel and PC based DAS <b>A/D and D/A Converters:</b> Types and Specifications of A/D and D/A Converters, Significance of X $\frac{1}{2}$ Digit Display	
	4.2	<b>Digital Multi-meter:</b> Block diagram, multi range measurement of voltage, current and resistance, specifications	
5.0		<b>Oscilloscopes</b>	08
	5.1	<b>Cathode Ray Oscilloscope:</b> Block Diagram based Study of CRO, Specifications, Controls, Sweep Modes, Role of Delay Line, Single- and Dual-Beam Dual-Trace CROs, Chop and Alternate Modes	
	5.2	<b>Measurement using Oscilloscope:</b> Measurement of Voltage, Frequency, Rise Time, Fall Time and Phase Difference. Lissajous Figures in Detection of Frequency and Phase	
	5.3	<b>Digital Storage Oscilloscope (DSO):</b> Block diagram based study of DSO, Study of features like Roll, Refresh, Storage Mode and Sampling Rate; Applications of DSO	
6.0		<b>Signal Analyzers</b>	06
	6.1	<b>Wave Analyzers:</b> Introduction to Harmonic, Total Harmonic Distortion Analyzer; Block Diagram and Applications of Wave Analyzers	
	6.2	<b>Spectrum and Network Analyzers:</b> Block Diagram and Applications	
		<b>Total</b>	<b>52</b>

**Text Books:**

1. C. S. Rangan, G.R. Sarma, and V.S.V. Mani, "*Instrumentation Devices and Systems*", Tata McGraw Hill, 9<sup>th</sup> edition, 2007
2. H. S. Kalsi, "*Electronics Instrumentation*", Tata McGraw Hill, 2<sup>nd</sup> Edition, 2009

**Reference Books:**

1. H. Oliver and J. M. Cage, "*Electronic Measurement and Instrumentation*", McGraw Hill, 3rd edition, 2008
2. W. Cooper and A. Helfric, "*Electronic Instrumentation and Measurement Techniques*", PHI, 4th edition, 2009
3. T. S. Rathore, "*Digital Measurement Techniques*", Narosa Publishing House, New Delhi, 2<sup>nd</sup> Edition, 2003
4. J. J. Carr, "*Elements of Electronic Instrumentation and Control*", Prentice Hall, 3rd edition, 2008

**Internal Assessment (IA):**

Two tests must be conducted which should cover at least 80% of syllabus. The average marks of both the test will be considered for final Internal Assessment.

**End Semester Examination:**

1. Question paper will comprise of 6 questions, each carrying 20 marks.
2. The students need to solve total 4 questions.
- 3: Question No.1 will be compulsory and based on entire syllabus.
- 4: Remaining question (Q.2 to Q.6) will be selected from all the modules.
- 5: Weightage of marks will be as per Blueprint.

Subject Code	Subject Name	Teaching Scheme			Credits Assigned			
		Theory	Practical	Tutorial	Theory	Practical	Tutorial	Total
ETC 406	Object Oriented Programming Methodology	02	02	--	--	01	--	01

Subject Code	Subject Name	Examination Scheme							
		Theory Marks				Term Work	Practical And Oral	Oral	Total
		Internal assessment			End Sem. Exam				
		Test 1	Test 2	Avg. Of Test 1 and Test 2					
ETC 406	Object Oriented Programming Methodology	--	--	--	--	25	50	-	75

**Pre-requisites:** Course in Structured Programming Approach/ Any Programming Language

**Course Objectives:**

- To understand the concept of Object Oriented Programming
- To help student to understand use of programming language such as JAVA to resolve problems.
- To impart problems understanding, analyzing skills in order to formulate Algorithms.
- To provide knowledge about JAVA fundamentals: data types, variables, keywords and control structures.
- To understand methods, arrays, inheritance, Interface, package and multithreading and concept of Applet.

**Course Outcomes:**

- Students will be able to code a program using JAVA constructs.
- Given an algorithm a student will be able to formulate a program that correctly implements the algorithm.
- Students will be able to generate different patterns and flows using control structures and use recursion in their programs.
- Students will be able to use thread methods, thread exceptions and thread priority.
- Students will implement method overloading in their code.
- Students will be able to demonstrate reusability with the help of inheritance.
- Students will be able to make more efficient programs.

Module No.	Unit No.	Topic	Hrs.
<b>1</b>		<b>Fundamental concepts of object oriented programming</b>	<b>4</b>
	1.1	Overview of Programming	
	1.2	Introduction to the principles of object-oriented programming : Classes, Objects, Messages, Abstraction, Encapsulation, Inheritance, Polymorphism, exception handling, and object-oriented containers	
	1.3	Differences and Similarity between C++ and JAVA	
<b>2</b>		<b>Fundamental of Java Programming</b>	<b>4</b>
	2.1	Features of Java	
	2.2	JDK Environment & tools	
	2.3	Structure of java program	
	2.4	Keywords , Data types, Variables, Operators, Expressions	
	2.5	Decision Making, Looping, Type Casting	
	2.6	Input output using scanner class	
<b>3</b>		<b>Classes and Objects</b>	<b>6</b>
	3.1	Creating Classes and objects	
	3.2	Memory allocation for objects	
	3.3	Passing parameters to Methods	
	3.4	Returning parameters	
	3.5	Method overloading	
	3.6	Constructor and finalize( )	
	3.7	Arrays : Creating an array	
	3.8	Types of Array : One Dimensional arrays ,Two Dimensional array, string	
<b>4</b>		<b>Inheritance , Interface and Package</b>	<b>6</b>
	4.1	Types of Inheritance : Single ,Multilevel, Hierarchical	
	4.2	Method Overriding, Super keyword, Final Keyword, Abstract Class	
	4.3	Interface	
	4.4	Packages	
<b>5</b>		<b>Multithreading</b>	<b>4</b>
	5.1	Life cycle of thread	
	5.2	Methods	
	5.3	Priority in multithreading	
<b>6</b>		<b>Applet</b>	<b>2</b>
	6.1	Applet Life cycle	
	6.2	Creating applet	
	6.3	Applet tag	
		<b>Total</b>	<b>26</b>

**Text Books**

1. Object-oriented *“programming with JAVA”*, Rajkumar Buyya, Mcgraw Hill
2. E Balgurusamy, *“Programming with JAVA”*, Tata McGraw Hill

**Reference Book**

1. Herbert Schildt, *“The Complete Reference JAVA”*, Tata McGraw Hill
2. Barry Holmes and Daniel T. Joyce, *“Object Oriented Programming with Java”*, Jones & Bartlett Learning

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Subject Code	Subject Name	Teaching Scheme			Credits Assigned			
		Theory	Practical	Tutorial	Theory	Practical	Tutorial	Total
ETL 304	Object Oriented Programming Methodology Laboratory	--	02	--	--	01	--	01

Subject Code	Subject Name	Examination Scheme								
		Theory Marks					Term Work	Practical And Oral	Oral	Total
		Internal assessment			End Sem. Exam					
		Test 1	Test 2	Avg. Of Test 1 and Test 2						
ETL 304	Object Oriented Programming Methodology Laboratory	--	--	--	--	25	50	-	75	

**Term Work:**

At least **10** experiments covering entire syllabus should be set to have well predefined inference and conclusion. Computation/simulation based experiments are also encouraged. The experiments should be students' centric and attempt should be made to make experiments more meaningful, interesting and innovative.

Term work assessment must be based on the overall performance of the student with every experiment graded from time to time. The grades will be converted to marks as per **Credit and Grading** System manual and should be added and averaged. Based on the above scheme grading and term work assessment should be done.

**The Practical / Oral examination will be based on entire syllabus.**

Subject Code	Subject Name	Teaching Scheme			Credits Assigned			
		Theory	Practical	Tutorial	Theory	Practical	Tutorial	Total
ETL 303	Circuits and Measurement Laboratory	--	02	--	--	01	--	01

Subject Code	Subject Name	Examination Scheme							
		Theory Marks				Term Work	Practical And Oral	Oral	Total
		Internal assessment			End Sem. Exam				
		Test 1	Test 2	Avg. Of Test 1 and Test 2					
ETL 303	Circuits and Measurement Laboratory	--	--	--	--	25	-	-	25

**Term Work:**

At least **10** experiments (5 from Circuits and Transmission lines and 5 from Electronics Instruments and Measurements) covering entire syllabus should be set to have well predefined inference and conclusion. Computation/simulation based experiments are also encouraged. The experiments should be students' centric and attempt should be made to make experiments more meaningful, interesting and innovative.

Term work assessment must be based on the overall performance of the student with every experiment graded from time to time. The grades converted into marks as per **Credit and Grading** System manual should be added and averaged. Based on this final term work grading and term work assessment should be done.

**The Practical / Oral examination will be based on entire syllabus.**



Sub Code	Subject Name	Teaching Scheme(Hrs.)			Credits Assigned			
		Theory	Practical	Tutorial	Theory	Practical	Tutorial	Total
ETS401	Applied Mathematics IV	04	--	01	04	--	01	05
ETC402	Analog Electronics II	04	--	--	04	--	--	04
ETC403	Microprocessor and Peripherals	04	--	--	04	--	--	04
ETC404	Wave Theory and Propagation	04	--	--	04	--	-	04
ETC 405	Signals and Systems	04	--	01	04	-	01	05
ETC406	Control Systems	04	--	--	04	--	-	04
ETL401	Analog Electronics II Laboratory	--	02	--	--	01	--	01
ETL402	Microprocessor and Peripherals Laboratory	--	02	--	--	01	--	01
ETL403	SSW Laboratory	--	02	--	--	01	--	01
<b>Total</b>		<b>24</b>	<b>06</b>	<b>02</b>	<b>24</b>	<b>03</b>	<b>02</b>	<b>29</b>

Subject Code	Subject Name	Examination Scheme							Total	
		Theory Marks				End Sem. Exam	Term Work	Practical and Oral		Oral
		Internal assessment			Avg. Of Test 1 and Test 2					
Test 1	Test 2									
ETS401	Applied Mathematics IV	20	20	20		80	25	--	--	125
ETC402	Analog Electronics II	20	20	20		80	--	--	--	100
ETC403	Microprocessor and Peripherals	20	20	20		80	--	--	--	100
ETC404	Wave Theory and Propagation	20	20	20		80	--	--	--	100
ETC 405	Signals and Systems	20	20	20		80	25	--	--	125
ETC406	Control Systems	20	20	20		80	--	--	--	100
ETL401	Analog Electronics II Laboratory	--	--	--		--	25	50	--	75
ETL402	Microprocessor and Peripherals Laboratory	--	--	--		--	25	50	--	75
ETL403	SSW Laboratory	--	--	--		--	25	25	--	50
<b>Total</b>		<b>--</b>	<b>--</b>	<b>120</b>		<b>480</b>	<b>125</b>	<b>125</b>	<b>--</b>	<b>850</b>

Subject Code	Subject Name	Teaching Scheme			Credits Assigned			
		Theory	Practical	Tutorial	Theory	Practical	Tutorial	Total
ETS 401	Applied Mathematics IV	04	--	01	04	--	01	05

Subject Code	Subject Name	Examination Scheme								
		Theory Marks				End Sem. Exam	Term Work	Practical	Oral	Total
		Internal assessment			Avg. Of Test 1 and Test 2					
		Test 1	Test 2							
ETS 401	Applied Mathematics IV	20	20	20	80	25	--	--	125	

#### Course Pre-requisite:

FE C 101 : Applied Mathematics I  
 FE C 201 : Applied Mathematics II  
 SE S 301 : Applied Mathematics III

#### Course Objective:

This course will present the method of calculus of variations (CoV), basic concepts of vector spaces, matrix theory, concept of ROC and residue theory with applications.

- To provide students with a sound foundation in Mathematics and prepare them for graduate studies in Electronics and Telecommunication Engg.
- To provide students with mathematics fundamental necessary to formulate, solve and analyze engg. problems.
- To provide opportunity for students to work as part of teams on multi disciplinary projects.

#### Expected Outcomes:

- Students will able to apply method of Calculus of Variations to specific systems, demonstrate ability to manipulate matrices and compute eigenvalues and eigenvectors, Identify and classify zeros, singular points, residues and their applications.
- Students will demonstrate an ability to identify formulate and solve Telecommunication Engg. problem using Applied Mathematics.
- Students who can participate and succeed in competitive exams like GATE, GRE.

Module No.	Unit No.	Topics	Hrs.
<b>1.0</b>	<b>1.0</b>	<b>Calculus of Variation</b>	<b>10</b>
	<b>1.1</b>	Euler's Langrange equation, solution of Euler's Langrange equation (only results for different cases for Function) independent of a variable, independent of another variable, independent of differentiation of a variable and independent of both variables	
	<b>1.2</b>	Isoperimetric problems, several dependent variables	
	<b>1.3</b>	<b>Functions involving higher order derivatives:</b> Rayleigh-Ritz method	
<b>2.0</b>	<b>2.0</b>	<b>Linear Algebra: Vector Spaces</b>	<b>12</b>
	<b>2.1</b>	<b>Vectors in n-dimensional vector space:</b> properties, dot product, cross product, norm and distance properties in n-dimensional vector space.	
	<b>2.2</b>	Metric spaces, vector spaces over real field, properties of vector spaces over real field, subspaces.	
	<b>2.3</b>	Norms and normed vector spaces	
	<b>2.4</b>	Inner products and inner product spaces	
	<b>2.5</b>	The Cauchy-Schwarz inequality, Orthogonal Subspaces, Gram-Schmidt process	
<b>3.0</b>	<b>3.0</b>	<b>Linear Algebra: Matrix Theory</b>	<b>15</b>
	<b>3.1</b>	Characteristic equation, Eigen values and Eigen vectors, properties of Eigen values and Eigen vectors	
	<b>3.2</b>	Cayley-Hamilton theorem, examples based on verification of Cayley-Hamilton theorem	
	<b>3.3</b>	Similarity of matrices, Diagonalisation of matrix	
	<b>3.4</b>	Functions of square matrix, derogatory and non-derogatory matrices	
	<b>3.5</b>	Quadratic forms over real field, reduction of Quadratic form to a diagonal canonical form, rank, index, signature of quadratic form, Sylvester's law of inertia, value-class of a quadratic form of definite, semi-definite and indefinite	
	<b>3.6</b>	Singular Value Decomposition	
<b>4.0</b>	<b>4.0</b>	<b>Complex Variables: Integration</b>	<b>15</b>
	<b>4.1</b>	<b>Complex Integration:</b> Line Integral, Cauchy's Integral theorem for simply connected regions, Cauchy's Integral formula	
	<b>4.2</b>	Taylor's and Laurent's series	
	<b>4.3</b>	Zeros, singularities, poles of $f(z)$ , residues, Cauchy's Residue theorem	
	<b>4.4</b>	Applications of Residue theorem to evaluate real Integrals of different types	
		<b>Total</b>	<b>52</b>

**Text books:**

- 1) A Text Book of Applied Mathematics Vol. I & II by P.N.Wartilar & J.N.Wartikar, Pune, Vidyarthi Griha Prakashan., Pune
- 2) Mathematical Methods in science and Engineering, A Datta (2012)
- 3) Higher Engg. Mathematics by Dr. B.S. Grewal, Khanna Publication

**Reference Books:**

- 1) Todd K.Moon and Wynn C. Stirling, Mathematical Methods and algorithms for Signal Processing, Pearson Education.
- 2) Kreyszig E., Advanced Engineering Mathematics, 9<sup>th</sup> edition, John Wiley, 2006.
- 3) Linear Algebra- Hoffman & Kunze (Indian editions) 2002
- 4) Linear Algebra- Anton & Torres (2012) 9<sup>th</sup> Indian Edition.
- 5) Complex Analysis – Schaum Series.

**Internal Assessment (IA):**

Two tests must be conducted which should cover at least 80% of syllabus. The average marks of both the tests will be considered for final Internal Assessment.

**End Semester Examination:**

1. Question paper will comprise of 6 questions, each carrying 20 marks.
2. The students need to solve total 4 questions.
- 3: Question No.1 will be compulsory and based on entire syllabus.
- 4: Remaining question (Q.2 to Q.6) will be selected from all the modules.
- 5: Weightage of marks will be as per Blueprint.

**Term Work:**

At least 08 assignments covering entire syllabus must be given during the **Class Wise Tutorial**. The assignments should be students' centric and an attempt should be made to make assignments more meaningful, interesting and innovative.

Term work assessment must be based on the overall performance of the student with every assignment graded from time to time. The grades will be converted to marks as per **Credit and Grading System** manual and should be added and averaged. Based on above scheme grading and term work assessment should be done.

Subject Code	Subject Name	Teaching Scheme			Credits Assigned			
		Theory	Practical	Tutorial	Theory	TW/Practical	Tutorial	Total
ETC 402	Analog Electronics II	4	--	--	4	01	--	05

Subject Code	Subject Name	Examination Scheme								
		Theory Marks				Term Work	Practical And Oral	Oral	Total	
		Internal assessment			End Sem. Exam					
		Test 1	Test 2	Avg. Of Test 1 and Test 2						
ETC 402	Analog Electronics II	20	20	20		80	25	50	--	175

**Course Pre-requisite:**

**ETC : 302 – Analog Electronics I**

**Course Objective:**

- To deliver the core concepts and reinforce the analytical skills learned in Electronic Devices and Circuits-I
- To motivate students to use MOS devices for designing and analyzing electronic Circuits which will help them to understand the fundamentals of VLSI design.

**Expected Outcomes:**

After completion of the course students will be able to

- Analyze and design multistage electronic Circuits.
- Differentiate between discrete and integrated biasing techniques.
- Differentiate between small signal and large signal Amplifiers.

Module No.	Unit No.	Topics	Hrs.
1.0	1.0	<b>Frequency Response of Amplifiers</b>	14
	1.1	<b>High Frequency Model:</b> High frequency hybrid-pi equivalent Circuits of BJT and MOSFET, Miller Effect and Miller capacitance, gain bandwidth product	
	1.1	<b>Single Stage Amplifiers :</b> Effect of capacitors (coupling, bypass, load) on frequency response of single stage BJT (CE, CC, CB configurations) , MOSFET (CS, CG, CD configuration) Amplifiers, low and high frequency response of BJT (CE, CB, CC) and MOSFET (CS, CG, CD) Amplifiers	
	1.2	<b>Multistage Amplifier:</b> Low and high frequency response of multistage (CE-CE, CS-CS), cascode (CE-CB, CS-CG) Amplifiers, Darlington pair, design of two stage Amplifiers	
2	2	<b>Differential Amplifiers</b>	10
	2.1	<b>BJT Differential Amplifiers:</b> Terminology and qualitative description, DC transfer characteristics, Small signal Analysis, differential and common mode gain, CMRR, differential and common mode input impedance	
		<b>MOSFET Differential Amplifiers:</b> DC Transfer characteristics, Small signal Analysis, differential and common mode gain, CMRR, differential and common mode input impedance	
3.0	3.0	<b>Integrated Circuits Biasing Techniques</b>	08
	3.1	<b>Current Mirror:</b> Two transistor (BJT, MOSFET) current source, current relationship, output resistance.	
	3.2	<b>Improved Current Source:</b> Three transistor (BJT, MOSFET) current source	
	3.3	<b>Special Current Source:</b> Cascode (BJT, MOSFET) current source, Wilson and Widlar current source	
4.0	4.0	<b>Power Amplifiers</b>	8
	4.1	<b>Power Devices:</b> Power BJTs, Power MOSFETs, Heat Sinks	
	4.2	<b>Classification:</b> Class A, Class B, Class AB and Class C operation, and performance parameters	
	4.3	<b>Transformer and Transformerless Amplifiers:</b> Transformer coupled Class A Amplifier, Class AB output stage with diode biasing, $V_{BE}$ multiplier biasing, input buffer transistors, Darlington configuration	
5.0	5.0	<b>Fundamentals of Operational Amplifier</b>	08
	5.1	<b>Fundamentals of Op-amp:</b> characteristics of op-amp, ideal and non ideal properties, High frequency effects on op-amp gain and phase, frequency response, Slew rate limitation,	
	5.2	<b>Linear and Nonlinear Circuits Operations of op-amps:</b> adder, subtractor, multiplier Circuits, integrator, differentiator, active filters (first order low and high pass)	
6.0	6.0	<b>DC Regulated Power Supply</b>	04
	6.1	<b>Series and Shunt Regulator:</b> Regulator performance parameters, Zener shunt regulator, transistorized series and shunt regulator	
		<b>Total</b>	<b>52</b>

**Text Books:**

1. Donald A. Neamen, Electronic Circuit Analysis and Design, TATA McGraw Hill, 2<sup>nd</sup> Edition
2. Adel S. Sedra, Kenneth C. Smith and Arun N Chandorkar, Microelectronic Circuits Theory and Applications, Fifth Edition, International Version, OXFORD International Students Edition

**Recommended Books:**

1. Electronic Devices and Circuits Salivan
2. Electronic Devices and Circuits Jacob Millima
3. Electronic Devices and Circuits Rashid

**Internal Assessment (IA):**

Two tests must be conducted which should cover at least 80% of syllabus. The average marks of both the tests will be considered for final Internal Assessment.

**End Semester Examination:**

1. Question paper will comprise of 6 questions, each carrying 20 marks.
2. The students need to solve total 4 questions.
- 3: Question No.1 will be compulsory and based on entire syllabus.
- 4: Remaining question (Q.2 to Q.6) will be selected from all the modules.
- 5: Weightage of marks will be as per Blueprint.

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Subject Code	Subject Name	Teaching Scheme			Credits Assigned			
		Theory	Practical	Tutorial	Theory	TW/ Practical	Tutorial	Total
ETC 402	Analog Electronics II Laboratory	--	02	--	--	01	--	01

Subject Code	Subject Name	Examination Scheme							
		Theory Marks				Term Work	Practical And Oral	Oral	Total
		Internal assessment			End Sem. Exam				
		Test 1	Test 2	Avg. Of Test 1 and Test 2					
ETC 402	Analog Electronics II Laboratory	--	--	--	--	25	50	--	75

**Term Work:**

At least **10** experiments covering entire syllabus should be set to have well predefined inference and conclusion. Computation/simulation based experiments are also encouraged. The experiments should be students' centric and attempt should be made to make experiments more meaningful, interesting and innovative.

Term work assessment must be based on the overall performance of the student with every experiment graded from time to time. The grades converted into marks as per **Credit and Grading** System manual should be added and averaged. Based on this final term work grading and term work assessment should be done.

**The Practical / Oral examination will be based on entire syllabus.**



Subject Code	Subject Name	Teaching Scheme			Credits Assigned			
		Theory	Practical	Tutorial	Theory	Practical	Tutorial	Total
ETC 403	Microprocessor and Peripherals	4	--	--	4	01	--	05

Subject Code	Subject Name	Examination Scheme							
		Theory Marks				Term Work	Practical and Oral	Oral	Total
		Internal assessment			End Sem. Exam				
		Test 1	Test 2	Avg. Of Test 1 and Test 2					
ETC403	Microprocessor and Peripherals	20	20	20	80	25	50	-	175

**Course Pre-requisite:**

ETC 303 : Digital Electronics

**Course Objective**

- To develop background knowledge and core expertise in microprocessor.
- To study the concepts and basic architecture of 8085, 8086, 80286, 80386, 80486 Pentium processor and Co-processor 8087.
- To know the importance of different peripheral devices and their interfacing to 8086.
- To know the design aspects of basic microprocessor.
- To write assembly language programs in microprocessor for various applications.

**Course Outcome**

- To impart knowledge on the architecture and software aspects of microprocessor 8086
- To write assembly language program in 8086 for various application.
- To provide a framework on the co-processor configurations.
- To create the various interfacing techniques with 8086 for various application.
- To give an overview on the architecture and basic concepts of advanced microprocessors.

Module No.	Unit No.	Topics	Hrs.
<b>1.0</b>		<b>Architecture of 8085 and 8086 Microprocessor</b>	<b>08</b>
	<b>1.1</b>	8085 Architecture and pin configuration.	
	<b>1.2</b>	8086 Architecture and organization, pin configuration.	
	<b>1.3</b>	Minimum and Maximum modes of 8086.	
	<b>1.4</b>	Read and Write bus cycle of 8086.	
<b>2.0</b>		<b>Instruction set and programming of 8086</b>	<b>10</b>
	<b>2.1</b>	8086 Addressing modes.	
	<b>2.2</b>	8086 Instruction encoding formats and instruction set.	
	<b>2.3</b>	Assembler directives.	
	<b>2.4</b>	8086 programming and debugging of assembly language program.	
<b>3.0</b>		<b>Peripherals interfacing with 8086 and applications.</b>	<b>10</b>
	<b>3.1</b>	8086-Interrupt structure.	
	<b>3.2</b>	Programmable Interrupt Controller 8259A.	
	<b>3.3</b>	Programmable Peripheral Interface 8255.	
	<b>3.4</b>	Programmable Interval Timer 8254.	
	<b>3.5</b>	DMA controller 8257	
	<b>3.6</b>	Interfacing 8259A, 8255, 8254, 8257 with 8086 and their applications.	
<b>4.0</b>		<b>ADC, DAC interfacing with 8086 and its application</b>	<b>08</b>
	<b>4.1</b>	Analog to Digital Converter (ADC) 0809	
	<b>4.2</b>	Digital to Analog Converter (DAC) 0808	
	<b>4.3</b>	Interfacing ADC 0809, DAC 0808 with 8086 and their Applications.	
	<b>4.4</b>	8086 based data Acquisition system.	
<b>5.0</b>		<b>8086 Microprocessor system design.</b>	<b>10</b>
	<b>5.1</b>	8087 Math coprocessor, its data types and interfacing with 8086.	
	<b>5.2</b>	Memory interfacing with 8086.	
<b>6.0</b>		<b>Advanced Microprocessor</b>	<b>06</b>
	<b>6.1</b>	Basic architectures of 80286, 80386, 80486 and Pentium processor.	
		<b>Total</b>	<b>52</b>

**Text Books:**

1. Gaonkar R.S.: "Microprocessor Architecture Programming and Applications with the 8085" Penram International Pub, 5<sup>th</sup> Edition.
2. John Uffenbeck: "8086/8088 family: "Design, Programming and Interfacing", Prentice Hall, 2<sup>nd</sup> Edition
3. B. B. Brey: "The Intel Microprocessors 8086/8088, 80186/80188, 80286, 80386, 80486, Pentium and Pentium Pro Processor", Pearson Pub, 8<sup>th</sup> Edition

**Reference Books:**

1. Hall D.V: "Microprocessor and Interfacing Programming and Hardware", Tata McGraw Hill, 2<sup>nd</sup> Edition.
2. A. K. Ray and K. M. Burchandi: "Advanced Microprocessor and Peripherals, Architecture Programming and Interfacing", Tata McGrawHill, 3<sup>rd</sup> Edition
3. Don Anderson, Tom Shanley: "Pentium Processor System Architecture", MindShare Inc., 2<sup>nd</sup> Edition
4. National Semiconductor: Data Acquisition Linear Devices Data Book
5. Intel Peripheral Devices: Data Book.

**Internal Assessment (IA):**

Two tests must be conducted which should cover at least 80% of syllabus. The average marks of both the test will be considered for final Internal Assessment.

**End Semester Examination:**

1. Question paper will comprise of 6 questions, each carrying 20 marks.
2. The students need to solve total 4 questions.
3. Question No.1 will be compulsory and based on entire syllabus.
4. Remaining question (Q.2 to Q.6) will be selected from all the modules.
5. Weightage of marks will be as per Blueprint.

Subject Code	Subject Name	Teaching Scheme			Credits Assigned			
		Theory	Practical	Tutorial	Theory	Practical	Tutorial	Total
ETC 403	Microprocessor and Peripherals Laboratory	--	01	--	01	01	--	01

Subject Code	Subject Name	Examination Scheme								
		Theory Marks				End Sem. Exam	Term Work	Practical and Oral	Oral	Total
		Internal assessment			Avg. Of Test 1 and Test 2					
		Test 1	Test 2							
ETC403	Microprocessor and Peripherals Laboratory	--	--	--	--	25	50	-	75	

**Term Work:**

At least **10** experiments covering entire syllabus should be set to have well predefined inference and conclusion. Computation/simulation based experiments are also encouraged. The experiments should be students' centric and attempt should be made to make experiments more meaningful, interesting and innovative.

Term work assessment must be based on the overall performance of the student with every experiment graded from time to time. The grades will be converted to marks as per **Credit and Grading** System manual and should be added and averaged. Based on the above scheme grading and term work assessment should be done.

**The Practical / Oral examination will be based on entire syllabus.**

Subject Code	Subject Name	Teaching Scheme (Hrs)			Credits Assigned			
		Theory	Practical	Tutorial	Theory	Practical	Tutorial	Total
ETC 404	Wave Theory and Propagation	4	--	--	4	--	01	05

Subject Code	Subject Name	Examination Scheme								
		Theory Marks					Term Work	Practical	Oral	Total
		Internal assessment			End Sem. Exam					
		Test 1	Test 2	Avg. Of Test 1 and Test 2						
ETC 404	Wave Theory and Propagation (WTP)	20	20	20	80	--	-	-	100	

**Course Objective:**

- To understand basic laws of electrostatics and magnetostatics in vector form.
- To understand the propagation of wave in different media like dielectric and conducting media by solving wave equation and find parameters of media.
- To calculate energy transported by means of electromagnetic waves from one point to another and to study polarization of waves.
- To solve electromagnetic problems using different numerical methods.
- To extend the students' understanding about the propagation of the waves by different types such as ground waves and space waves.
- To study the factors affecting the wave during its propagation.
- To understand sky wave propagation; related parameters such as MUF, skip distance and critical frequency.

**Expected Outcomes:**

- Ability to find nature of electric or magnetic field produced due to different charge distributions.
- Ability to understand working of different equipments based on electromagnetic used in day to day life.
- Knowledge of behavior of EM waves and travelling of waves in free space as well as media.
- Able to find conditions for loss of signal.
- Able to apply numerical methods for designing antennas.
- An ability to select proper parameters for propagation of the waves by considering the factors affecting.
- Any ability to identify and solve problems related to the propagation of waves.
- To understand the basics of wave propagation required for the study of antennas.

Module No.	Unit No.	Topics	Hrs.
<b>1.0</b>		<b>Basic Laws of electromagnetic &amp; Maxwell's equations</b>	<b>13</b>
	<b>1.1</b>	<b>Fundamental laws of electromagnetic fields:</b> Coulomb's law, Gauss's law, Bio-Savart's law, Ampere's law, Poisson's and Laplace equations	
	<b>1.2</b>	<b>Boundary conditions:</b> Static electric and magnetic fields	
	<b>1.3</b>	<b>Maxwell's equations:</b> Integral and differential form for static and time varying fields and its interpretations	
	<b>1.4</b>	<b>Applications of electromagnetic fields:</b> Ink-jet printer, CRO, electromagnetic pump	
<b>2.0</b>		<b>Uniform plane wave equation and power balance</b>	<b>08</b>
	<b>2.1</b>	<b>Wave equation:</b> Derivation and its solution in Cartesian co-ordinates	
	<b>2.2</b>	<b>Solution of wave equations:</b> Partially conducting media, perfect dielectrics and good conductors, concept of skin dept	
	<b>2.3</b>	<b>Electromagnetic Power:</b> Poynting Vector and Power Flow in free space and in dielectric, conducting media	
<b>3.0</b>		<b>Plane Wave Propagation</b>	<b>06</b>
	<b>3.1</b>	<b>Polarization of wave;</b> Elliptical. Linear and Circular	
	<b>3.2</b>	<b>Propagation in different mediums:</b> Behavior of waves for normal and oblique incidence in dielectrics and conducting media, propagation in dispersive media	
<b>4.0</b>		<b>Computational Electromagnetics</b>	<b>08</b>
	<b>4.1</b>	<b>Finite Difference Method (FDM):</b> Neumann type and mixed boundary conditions, Iterative solution of finite difference equations, solutions using band matrix method	
	<b>4.2</b>	<b>Finite Element Method (FEM):</b> Triangular mesh configuration, Finite element discretization, Element governing equations, Assembling all equations and solving resulting equations	
	<b>4.3</b>	<b>Method of Moment (MOM):</b> Field calculations of conducting wire, parallel conducting wires and complicated geometries	
<b>5.0</b>		<b>Radio Wave Propagation</b>	<b>10</b>
	<b>5.1</b>	<b>Types of wave propagation:</b> Ground, space and surface wave propagation, tilt and surface waves, impact of imperfect earth and earth's behavior at different frequencies	
	<b>5.2</b>	<b>Space wave propagation:</b> Effect of imperfection of earth, curvature of earth, effect of interference zone, shadowing effect of hills and building, atmospheric absorption, Super-refraction, scattering phenomena, troposphere propagation and fading	
<b>6.0</b>		<b>Sky Wave Propagation</b>	<b>07</b>
	<b>6.1</b>	<b>Reflection and Refraction of waves:</b> Ionosphere and Earth magnetic field effect	
	<b>6.2</b>	<b>Measures of Ionosphere Propagation:</b> Critical frequency, Angle of incidence, Maximum unstable frequency, Skip distance, Virtual height, Variations in ionosphere and Attenuation and fading of waves in ionosphere	
		<b>Total</b>	<b>52</b>

**Text Books:**

1. J.A. Administer, "**Electromagnetic**", McGraw Hill Companies, 2<sup>nd</sup> Edition, 2006
2. Bhag Guru and Huseyin Hiziroglu, "**Electromagnetic field theory fundamentals**", Cambridge University Press, 2<sup>nd</sup> Edition, 2010.
3. J.D. Kraus, R.J. Marhefka, A.S. Khan "**Antennas & Wave Propagation**", McGraw Hill Publications, 4<sup>th</sup> Edition, 2011

**Reference Books**

1. R.K. Shevgaonkar, Electromagnetic Waves, TATA McGraw Hill Companies, 3<sup>rd</sup> Edition, 2009
2. R.L. Yadava, Antenna & Wave Propagation, PHI Publications, 1<sup>st</sup> Edition, 2011
3. Edward C. Jordan, Keth G. Balmin, Electromagnetic Waves & Radiating Systems, Pearson Publications, 2<sup>nd</sup> Edition, 2006
4. Matthew N.D. SADIKU, Principles of Electromagnetics, Oxford International Student 4<sup>th</sup> Edition, 2007
5. W.H. Hayt, J.A. Buck, Engineering Electromagnetics, McGraw Hill Publications, 7<sup>th</sup> Edition, 2006.

**Internal Assessment (IA):**

Two tests must be conducted which should cover at least 80% of syllabus. The average marks of both the test will be considered for final Internal Assessment.

**End Semester Examination:**

1. Question paper will comprise of 6 questions, each carrying 20 marks.
2. The students need to solve total 4 questions.
- 3: Question No.1 will be compulsory and based on entire syllabus.
- 4: Remaining question (Q.2 to Q.6) will be selected from all the modules.
- 5: Weightage of marks will be as per Blueprint.

Subject Code	Subject Name	Teaching Scheme			Credits Assigned			
		Theory	Practical	Tutorial	Theory	Practical	Tutorial	Total
ETC 406	Signals and Systems	04	--	01	04	--	01	05

Subject Code	Subject Name	Examination Scheme								
		Theory Marks					Term Work	Practical And Oral	Oral	Total
		Internal assessment			End Sem. Exam					
		Test 1	Test 2	Avg. Of Test 1 and Test 2						
ETC 406	Signals and Systems	20	20	20	80	25	--	--	125	

**Course Pre-requisite :**

**ETS : 301 : Applied Mathematics III**

**ETC : 204 : Circuits and Transmission Lines**

**Course Objective:**

- To introduce students to the idea of signal and system analysis and characterization in time and frequency domain.
- To provide foundation of signal and system concepts to areas like communication, control and comprehend applications of signal processing in communication systems.

**Course Outcomes:**

- Students will be able to understand significance of signals and systems in the
- Students will be able to conduct experiments interpret and analyze signal and report results.
- Students will be able to evaluate the time and frequency response of continuous and discrete time, system which is useful in understanding behavior of Electronics circuits and communication systems.



Mod ule No.	Uni t No.	Topics	Hr s.
1.0		<b>Overview of signals and systems</b>	<b>06</b>
	1.1	<b>Introduction:</b> Signals, systems, examples of systems for controls and communication, sampling theorem, sampling of continuous time signals, elementary signals, exponential, sine, step, impulse, ramp, rectangular, triangular and operations on signals	
	1.2	<b>Classification of signals:</b> Continuous and discrete time, deterministic and non deterministic, periodic and aperiodic, symmetric (even) and asymmetric (odd), energy and power, causal and anti-causal signals.	
2.0	2.0	<b>Time domain analysis of Continuous Time and Discrete Time systems</b>	<b>12</b>
	2.1	<b>Classification of systems:</b> Static and dynamic, time variant and time invariant, linear and nonlinear, causal and noncausal, stable and unstable systems.	
	2.2	<b>Linear Time Invariant (LTI) systems:</b> Representation of systems using differential /difference equation, Impulse, step and exponential response, system stability, examples on applications of LTI systems, convolution, impulse response of interconnected systems, auto-correlation, cross correlation, properties of correlation, analogy between correlation and convolution, total response of a system	
3.0		<b>Laplace Transform</b>	<b>06</b>
3.0	3.1	<b>Overview of Laplace Transform:</b> Laplace Transform and properties, relation between continuous time Fourier Transform and Laplace Transform, unilateral Laplace Transform.	
	3.2	<b>Analysis continuous time LTI systems using Laplace Transform:</b> Transfer Function, causality and stability of systems, solution of Differential Equations using Laplace Transform.	
4.0		<b>Z - Transform</b>	<b>08</b>
	4.1	Z-Transform of finite and infinite duration sequences, relation between discrete time Fourier Transform and z-Transform, properties, Inverse z-Transform, one sided z-Transform.	
	4.2	<b>Analysis of discrete time LTI systems using z-Transform:</b> Transfer Function, causality and stability of systems, frequency response, relation between Laplace Transform and z-Transform.	
	4.3	<b>Fourier series of continuous and discrete time signals</b>	
5.0		<b>Fourier Series</b>	<b>10</b>
	5.1	<b>Review of Fourier series:</b> trigonometric and exponential Fourier series representation of signals, magnitude and phase spectra, power spectral density and bandwidth. Gibbs phenomenon.	
	5.2	<b>Properties of Fourier Series:</b> Linearity, time shifting, time reversal, frequency shifting, time scaling, differentiation, symmetry. Parseval's relation. Examples based on properties, analogy between Continuous Time Fourier Series (CTFS) and Discrete Time Fourier Series (DTFS).	
	5.3	Continuous Time Fourier Transform (CTFT) and Discrete Time Fourier Transform (DTFT)	
6.0		<b>Continuous Time Fourier Transform (CTFT) and Discrete Time Fourier Transform (DTFT)</b>	<b>10</b>
	6.1	<b>Fourier Transform:</b> Fourier Transform and Inverse Fourier Transform on periodic and non-periodic signals, limitations of Fourier Transform and need for Laplace and z-Transform	
	6.2	<b>Properties of Fourier Transform:</b> Linearity, time shifting, time reversal, frequency shifting, time and frequency scaling, modulation, convolution in time domain, differentiation in time domain, differentiation in frequency domain, symmetry. Parseval's relation. Energy, power spectral density and bandwidth. Definition and problems on DTFT	
		<b>Total</b>	<b>52</b>

**Text books**

1. Nagor Kani, Signals and Systems, Tata McGraw Hill, Third Edition, 2011.
2. B.P. Lathi, Principles of Linear Systems and Signals, Oxford, Second Edition, 2010.
3. Simon Haykin and Barry Van Veen, Signals and Sytems, John Wiley and Sons, Second Edition, 2004.

**Reference books**

- 1) Hwei. P Hsu, Signals and Systems, Tata McGraw Hill, Third edition, 2010
- 2) V. Krishnaveni and A.Rajeshwari, Signals and Systems, Wiley-India, First Edition 2012.
- 3) Narayana Iyer, Signals and Systems, Cenage Learning, First Edition 2011.
- 4) Michael J Roberts, Fundamentals of Signals and systems, Tata McGraw Hill, special Indian Economy edition, 2009.
- 5) Rodger E Ziemer, William H. Tranter and D. Ronald Fannin, Signals and Systems, Pearson Education, Fourth Edition 2009.
- 6) Alan V. Oppenheim, Alan S. Willsky and S. Hamid Nawab, Signals and Systems, Prentice-Hall of India, Second Edition, 2002.

**Internal Assessment (IA):**

Two tests must be conducted which should cover at least 80% of syllabus. The average marks of both the test will be considered as final IA marks

**End Semester Examination:**

1. Question paper will comprise of 6 questions, each carrying 20 marks.
2. The students need to solve total 4 questions.
- 3: Question No.1 will be compulsory and based on entire syllabus.
- 4: Remaining question (Q.2 to Q.6) will be selected from all the modules.
- 5: Weightage of marks will be as per Blueprint.

**Term Work:**

At least 08 assignments covering entire syllabus must be given during the **Class Wise Tutorial**. The assignments should be students' centric and an attempt should be made to make assignments more meaningful, interesting and innovative.

Term work assessment must be based on the overall performance of the student with every assignment graded from time to time. The grades will be converted to marks as per **Credit and Grading System** manual and should be added and averaged. Based on above scheme grading and term work assessment should be done.

Subject Code	Subject Name	Teaching Scheme			Credits Assigned			
		Theory	Practical	Tutorial	Theory	Practical	Tutorial	Total
ETC 405	Control Systems	04	02	--	04	--	--	04

Subject Code	Subject Name	Examination Scheme								
		Theory Marks					Term Work	Practical And Oral	Oral	Total
		Internal assessment			End Sem. Exam					
		Test 1	Test 2	Avg. Of Test 1 and Test 2						
ETC 405	Control Systems	20	20	20	80	--	--	--	100	

**Pre-requisite Topics:**

Dynamics; Differential Equations; Laplace Transforms.

**Course Objective:**

Objectives of this course are:

- To teach the fundamental concepts of Control systems and mathematical modeling of the system.
- To study the concept of time response and frequency response of the system.
- To teach the basics of stability analysis of the system

**Course Outcomes:**

The outcomes of this course are:

- Students will be able to derive the mathematical model of different type of the systems.
- Students will understand the basic concepts of control system.
- Students will understand the analysis of systems in time and frequency domain.
- Students will be able to apply the control theory to design the conventional controllers widely used in the industries.

Module No.	Unit No.	Topics	Hrs.
1.0		<b>Introduction to Control System Analysis</b>	08
	1.1	<b>Introduction:</b> Open loop and closed loop systems, feedback and feed forward control structure, examples of control systems.	
	1.2	<b>Modeling:</b> Types of models; Impulse response model; State variable model; Transfer Function model.	
	1.3	<b>Dynamic Response:</b> Standard test signals; Transient and steady state behavior of first and second order systems; Steady state errors in feedback control systems and their types.	
2.0		<b>Mathematical Modeling Of Systems</b>	08
	2.1	<b>Transfer Function models of various systems:</b> Models of mechanical systems; Models of electrical systems, Block diagram reduction; Signal flow graph and the Mason's gain rule.	
3.0		<b>State Variable Models</b>	10
	3.1	<b>State Variable Models Of Various Systems:</b> State variable models of mechanical systems; State variable models of electrical systems	
	3.2	<b>State Transition Equation:</b> Concept of state transition matrix; Properties of state transition matrix; Solution of homogeneous systems; solution of non-homogeneous systems.	
	3.3	<b>Controllability and Observability:</b> Concept of controllability; Controllability analysis of LTI systems; Concept of observability; Observability analysis of LTI systems.	
4.0		<b>Stability Analysis In Time Domain</b>	06
	4.1	<b>Concepts of Stability:</b> Concept of absolute, relative and robust stability; Routh stability criterion. ; Lag compensator; Lead compensator.	
	4.2	<b>Root Locus Analysis:</b> Root-locus concepts; General rules for constructing root-locus; Root-locus analysis of control systems.	
5.0		<b>Stability Analysis In Frequency Domain</b>	08
	5.1	<b>Introduction:</b> Frequency domain specifications, Response peak and peak resonating frequency; Relationship between time and frequency domain specification of system; Stability margins.	
	5.2	<b>Bode plot:</b> Magnitude and phase plot; Method of plotting Bode plot; Stability margins on the Bode plots; Stability analysis using Bode plot.	
	5.3	<b>Nyquist Criterion:</b> Polar plots, Nyquist stability criterions; Nyquist plot; Gain and phase margins.	
6.0		<b>Optimal and Adaptive Control Systems</b>	12
	6.1	<b>Optimal control:</b> Performance measure for optimal control problems, the principle of optimality, concept of dynamic programming, Hamilton-Jacobi-Bellman Equation, Fundamental of a single Function, Functions involving several independent Functions, constrained minimization of Functions	
	6.2	<b>Adaptive Control Systems:</b> model reference approach for controller design. Neuro-Fuzzy: adaptive control (only concept)	
		<b>Total</b>	<b>52</b>

**Text books:**

1. Nagrath, M.Gopal, "**Control System Engineering**", Tata McGraw Hill.
2. K.Ogata, "**Modern Control Engineering, Pearson Education**", III<sup>rd</sup> edition.
3. Benjamin C.Kuo, "**Automatic Control Systems, Pearson education**", VII<sup>th</sup> edition.

**Reference Books:**

1. Madam Gopal, Control Systems Principles and Design, Tata McGraw hill, seventh edition, 1997.
2. Norman, Control System Engineering, John Wiley & sons, 3rd edition.
3. Curtis Johnson, Process Control Instrumentation Technology, Pearson education fourth edition.

**Internal Assessment (IA):**

Two tests must be conducted which should cover at least 80% of syllabus. The average marks of both the test will be considered as final IA marks

**End Semester Examination:**

1. Question paper will comprise of 6 questions, each carrying 20 marks.
2. The students need to solve total 4 questions.
- 3: Question No.1 will be compulsory and based on entire syllabus.
- 4: Remaining question (Q.2 to Q.6) will be selected from all the modules.
- 5: Weightage of marks will be as per Blueprint.

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Subject Code	Subject Name	Teaching Scheme			Credits Assigned			
		Theory	Practical	Tutorial	Theory	Practical	Tutorial	Total
ETL 403	SSW Laboratory	--	02	--	--	01	--	01

Subject Code	Subject Name	Examination Scheme								
		Theory Marks					Term Work	Practical And Oral	Oral	Total
		Internal assessment			End Sem. Exam					
		Test 1	Test 2	Avg. Of Test 1 and Test 2						
ETL 403	SSW Laboratory	--	--	--	--	25	25	-	50	

### Objectives

- Students will demonstrate an ability to design a system, components or process as per needs and specifications.
- Students will demonstrate an ability to visualize and work on laboratory and multi disciplinary task.
- Students will demonstrate skills to use modern Engineering tools, software's and equipments to analyze problems.

### Term Work:

At least 10 simulation based experiments from Analog Electronics, Digital Electronics, Circuits and Transmission, Microprocessor, Signals and Systems and Wave Theory and Propagation should be set to have well predefined inference and conclusion, Computation/ simulation based experiments are also encouraged. The experiments should be students centric and attempt should be made to make experiments more meaningful, interesting and innovative.

Term work assessment must be based on the overall performance of the student with every experiment graded from time to time. The grades converted into marks as per Credit and Grading System manual should be added and averaged. Based on this final term work grading and term work assessment should be done. It is advisable to use required application softwares for simulation based experiments. Use open source software should be encouraged.

**Oral examination will be based on simulation experiments.**